

**Search Notes**

Application/Control No.

10/726,247

Examiner

Le Nguyen

Applicant(s)/Patent under  
Reexamination

AMUNDSON ET AL.

Art Unit

2174

**SEARCHED**

| Class | Subclass | Date      | Examiner |
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| 715   | 740      | 1/18/2007 | LVN      |
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**INTERFERENCE SEARCHED**

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| US-PGPub, USPAT:<br>715/740 |          | 1/18/2007 | LVN      |

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|  | DATE      | EXMR |
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| inventor name search   | 1/14/2007 | LVN  |
| US-PGPub, USPAT: 715/740,718,<br>771,864,963,970; 700/276-278,296,<br>65,83; 236/46R,47,49.1,49.3,94;<br>165/238,239,240,242,265,268 | 1/17/2007 | LVN  |
| IEEE Xplore, ACM Digital Library   | 1/22/2007 | LVN  |
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